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 Nuclear Science Symposium, 1997. IEEE , 9-15 Nov. 1997
 Pages:276 - 280 vol.1

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Legg, P.J.; Tur, M.; Regev, H.; Cornwell, W.D.; Shabeer, M.; Andonovic, I.;
 Lightwave Technology, Journal of , Volume: 14 , Issue: 10 , Oct. 1996
 Pages:2117 - 2125

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